

Characterization of Thin and Selective Film Depositions on V-Groove ASD Test Structures



Figure 1: Principle of ASD test chip

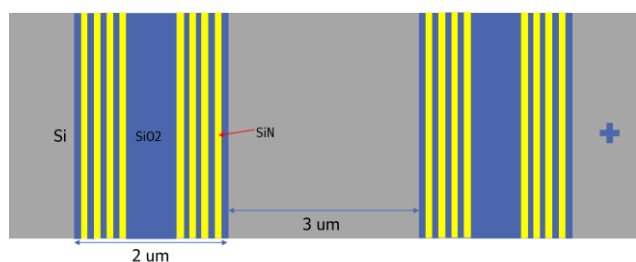


Figure 2: Layer Arrangement

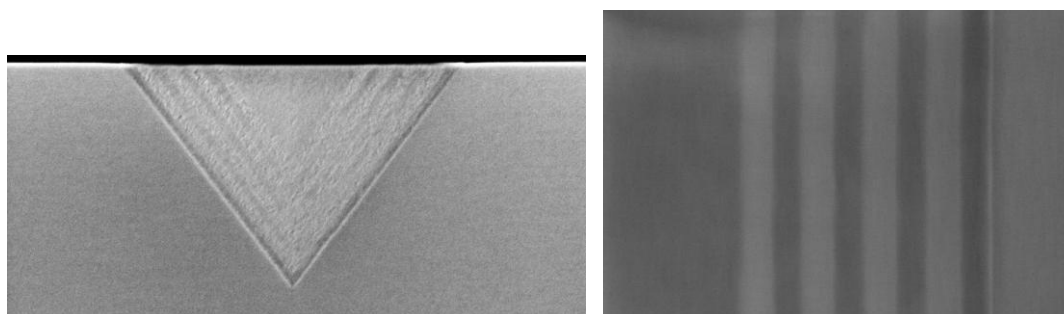


Figure 3: X-section and top-down view

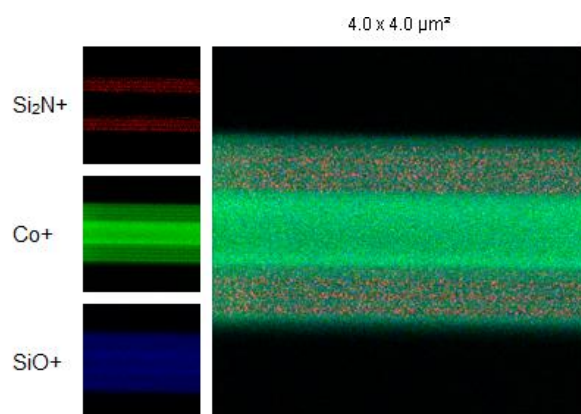


Figure 4: TOF-SIMS Analysis of selective Co ALD